









SN54AHCT00, SN74AHCT00

## SCLS229L - OCTOBER 1995 - REVISED MAY 2023

## **SNx4AHCT00 Quadruple 2-Input Positive-NAND Gates**

#### 1 Features

- Operating range of 4.5 V to 5.5 V
- Low power consumption, 10-µA maximum I<sub>CC</sub>
- ±8-mA output drive at 5 V
- Inputs are TTL-voltage compatible
- Latch-up performance exceeds 250 mA per JESD

## 2 Applications

- Enable or disable a digital signal
- Controlling an indicator LED
- Translation between communication modules and system controllers

## 3 Description

The 'AHCT00 devices perform the Boolean function Y =  $\overline{A \cdot B}$  or Y =  $\overline{A}$  +  $\overline{B}$  in positive logic.

#### Package Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
	J (CDIP, 14)	19.56 mm × 6.67 mm
SN54AHCT00	W (CFP, 14)	9.21 mm × 5.97 mm
	FK (LCCC, 20)	8.89 mm × 8.89 mm
	D (SOIC , 14)	8.65 mm × 3.91 mm
	DB (SSOP, 14)	6.20 mm × 5.30 mm
	DGV (TVSOP, 14)	3.60 mm × 4.40 mm
SN74AHCT00	N (PDIP, 14)	19.30 mm × 6.35 mm
	NS (SOP, 14)	10.30 mm × 5.30 mm
	RGY (QFN, 14)	3.50 mm × 3.50 mm
	BQA (WQFN, 14)	3.00 mm × 2.50 mm

For all available packages, see the orderable addendum at the end of the data sheet.



Logic Diagram, Each Gate (Positive Logic)



## **Table of Contents**

1 Features	1	8.2 Functional Block Diagram	9
2 Applications		8.3 Feature Description	
3 Description		8.4 Device Functional Modes	
4 Revision History		9 Application and Implementation	. 11
5 Pin Configuration and Functions		9.1 Application Information	11
6 Specifications	<u>5</u>	9.2 Typical Application	
6.1 Absolute Maximum Ratings		9.3 Power Supply Recommendations	13
6.2 ESD Ratings		9.4 Layout	
6.3 Recommended Operating Conditions	5	10 Device and Documentation Support	
6.4 Thermal Information	6	10.1 Documentation Support	. 14
6.5 Electrical Characteristics	6	10.2 Receiving Notification of Documentation Updates	14
6.6 Switching Characteristics		10.3 Support Resources	. 14
6.7 Noise Characteristics	6	10.4 Trademarks	
6.8 Operating Characteristics	7	10.5 Electrostatic Discharge Caution	14
7 Parameter Measurement Information	8	10.6 Glossary	
8 Detailed Description	9	11 Mechanical, Packaging, and Orderable	
8.1 Overview		Information	. 14

## **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	hanges from Revision K (July 2003) to Revision L (May 2023)	Page
•	Updated the Features section	1
•	Updated the Applications section	1
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Added BQA (WQFN) package information	1
•	Added the Package Information table	1
	Added the Test and SI table	
•	Added the Detailed Description sections	9
•	Added the Application and Implementation sections	11



## **5 Pin Configuration and Functions**

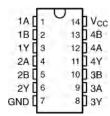


Figure 5-1. SN54AHCT00 J or W Package, 14-Pin CDIP or CFP SN74AHCT00 D, DB, DGV, N, NS, or PW Package, 14-Pin SOIC, SSOP, TVSOP, PDIP, SOP, or TSSOP (Top View)

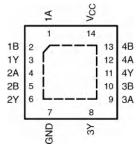


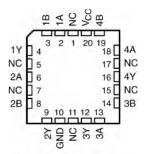
Figure 5-2. SN74AHCT00 RGY, BQA Package, 14-Pin QFN, WQFN (Transparent Top View)

Table 5-1. Pin Functions

	PIN	TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
1A	1	I	Channel 1, Input A
1B	2	I	Channel 1, Input B
1Y	3	0	Channel 1, Output Y
2A	4	I	Channel 2, Input A
2B	5	I	Channel 2, Input B
2Y	6	0	Channel 2, Output Y
3A	9	0	Channel 3, Output Y
3B	10	I	Channel 3, Input A
3Y	8	I	Channel 3, Input B
4A	12	0	Channel 4, Output Y
4B	13	I	Channel 4, Input A
4Y	11	I	Channel 4, Input B
GND	7	G	Ground
V <sub>CC</sub>	14	Р	Positive Supply

<sup>(1)</sup> Signal Types: I = Input, O = Output, I/O = Input or Output, P = Power Supply, G = Ground.





NC - No internal connection

Figure 5-3. SN54AHCT00 FK Package, 14-Pin LCCC (Top View)

**Table 5-2. Pin Functions** 

	PIN	TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.	I I PEV	DESCRIPTION
1A	2	I	Channel 1, Input A
1B	3	I	Channel 1, Input B
1Y	4	0	Channel 1, Output Y
2A	6	I	Channel 2, Input A
2B	8	I	Channel 2, Input B
2Y	9	0	Channel 2, Output Y
3A	13	0	Channel 3, Output Y
3B	14	I	Channel 3, Input A
3Y	12	I	Channel 3, Input B
4A	18	0	Channel 4, Output Y
4B	19	I	Channel 4, Input A
4Y	16	I	Channel 4, Input B
NC	1, 5, 7, 11, 15, 17	_	No Connection
GND	10	G	Ground
V <sub>CC</sub>	20	Р	Positive Supply

(1) Signal Types: I = Input, O = Output, I/O = Input or Output, P = Power Supply, G = Ground.



## **6 Specifications**

#### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
VI	Input voltage range <sup>(2)</sup>		-0.5	7	V
Vo	Output voltage range <sup>(2)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < -0.5 V		-20	mA
I <sub>OK</sub>	Output clamp current	$V_{O}$ < -0.5 V or $V_{O}$ > $V_{CC}$ + 0.5 V		±20	mA
Io	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>		±25	mA
	Continuous output current through	Continuous output current through V <sub>CC</sub> or GND		±50	mA
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

#### 6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	V
V (ESD)	Electrostatic discriarge	Charged device model (CDM), per ANSI/ESDA/JEDEC JS-002 <sup>(2)</sup>	±1000	V

<sup>1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

## **6.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted) (1)

		SN54AH	ICT00	SN74AH	UNIT	
		MIN	MAX	MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5.5	4.5	5.5	V
V <sub>IH</sub>	High-level input voltage	2		2		V
V <sub>IL</sub>	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current		-8		-8	mA
I <sub>OL</sub>	Low-level output current		8		8	mA
Δt/Δν	Input transition rise or fall rate		20		20	ns/V
T <sub>A</sub>	Operating free-air temperature	-55	125	-40	85	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



#### **6.4 Thermal Information**

			SN74AHCT00								
THE	ERMAL METRIC(1)	D (SOIC)	DB (SSOP)	DGV (TVSOP)	N (PDIP	NS (SOP)	PW (TSSOP)	RGY (VQFN)	BQA (WQFN)	UNIT	
		14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	14 PINS		
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	86	96	127	80	76	113	47	88.3	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

#### 6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIO	NIC	V	Т	<sub>A</sub> = 25°C		SN54Al	ICT00	SN74AH	HCT00	UNIT
PARAMETER	TEST CONDITIO	V <sub>CC</sub>	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
V <sub>OH</sub>	I <sub>OH</sub> = -50 μA		4.5 V	4.4	4.5		4.4		4.4		V
∨он	I <sub>OH</sub> = -8 mA		4.5 V	3.94			3.8		3.8		V
V <sub>OL</sub>	I <sub>OL</sub> = 50 μA		4.5 V			0.1		0.1		0.1	V
VOL	I <sub>OL</sub> = 8 mA					0.36		0.44		0.44	'
I <sub>I</sub>	V <sub>I</sub> = 5.5 V or GND		0 V to 5.5 V			±0.1		±1 <sup>(1)</sup>		±1	μΑ
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	I <sub>O</sub> = 0	5.5 V			2		20		20	μΑ
ΔI <sub>CC</sub> (2)	One input at 3.4 V, Oth at V <sub>CC</sub> or GND	ner inputs	5.5 V			1.35		1.5		1.5	mA
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND		5 V		2	10				10	pF

- (1) On products compliant to MIL-PRF-38535, this parameter is not production tested at V<sub>CC</sub> = 0 V.
- (2) This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V<sub>CC</sub>.

#### 6.6 Switching Characteristics

over recommended operating free-air temperature range,  $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$  (unless otherwise noted) (see Figure 7-1)

					, 00							
PARAMETER		FROM	то	LOAD	1	Γ <sub>A</sub> = 25°C		SN54AH	ICT00	SN74AI	НСТ00	UNIT
	PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	OMIT
	t <sub>PLH</sub>	A or P	V	C <sub>1</sub> = 15 pF		5 <sup>(1)</sup>	6.9 <sup>(1)</sup>	1 <sup>(1)</sup>	8 <sup>(1)</sup>	1	8	no
	t <sub>PHL</sub>	A or B	Ţ	CL = 15 pr		5 <sup>(1)</sup>	6.9 <sup>(1)</sup>	1 <sup>(1)</sup>	8 <sup>(1)</sup>	1	8	ns
	t <sub>PLH</sub>	A or B	V	C <sub>1</sub> = 50 pF		5.5	7.9	1	9	1	9	ns
	t <sub>PHL</sub>	A or B	<b>'</b>	OL = 30 pr		5.5	7.9	1	9	1	9	115

<sup>(1)</sup> On products compliant to MIL-PRF-38535, this parameter is not production tested.

#### 6.7 Noise Characteristics

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C (see}^{(1)})$ 

	PARAMETER	SN	74AHCT00	)	UNIT
	FARAINETER	MIN	TYP	MAX	ONIT
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.4	0.8	V
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>		-0.4	-0.8	V
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>		4.5		V
V <sub>IH(D)</sub>	High-level dynamic input voltage	2			V
$V_{IL(D)}$	Low-level dynamic input voltage			0.8	V

(1) Characteristics are for surface-mount packages only.



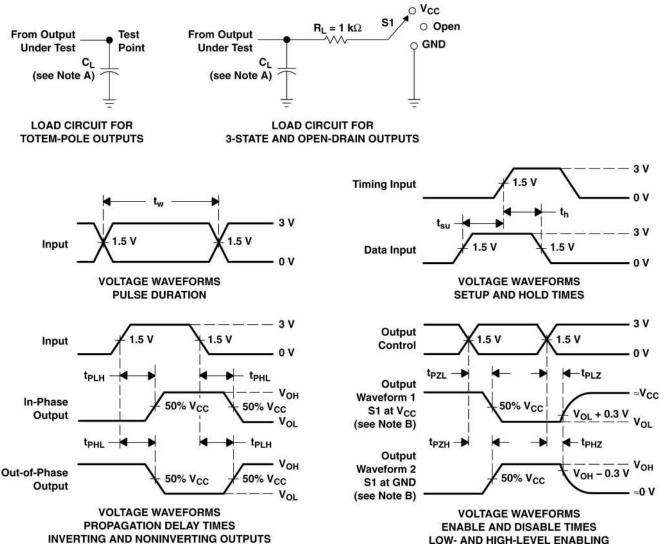
## **6.8 Operating Characteristics**

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ 

	PARAMETER	TEST CO	TYP	UNIT	
C <sub>pd</sub>	Power dissipation capacitance	No load,	f = 1 MHz	10.5	pF



#### 7 Parameter Measurement Information



- A. C<sub>L</sub> includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_0 = 50 \Omega$ ,  $t_r \leq 3$  ns.  $t_f \leq 3$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.

Figure 7-1. Load Circuit and Voltage Waveforms

Table 7-1. Test and SI

TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>CC</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND
Open Drain	V <sub>CC</sub>

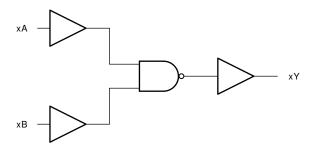


## 8 Detailed Description

#### 8.1 Overview

This device contains four independent 2-input NAND Gates. Each gate performs the Boolean function  $Y = \overline{A \bullet B}$  in positive logic.

#### 8.2 Functional Block Diagram



## 8.3 Feature Description

#### 8.3.1 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads, so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

#### 8.3.2 TTL-Compatible CMOS Inputs

This device includes TTL-compatible CMOS inputs. These inputs are specifically designed to interface with TTL logic devices by having a reduced input voltage threshold.

TTL-compatible CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law ( $R = V \div I$ ).

TTL-compatible CMOS inputs require that input signals transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and could cause oscillations. More details can be found in the *Implications of Slow or Floating CMOS Inputs* application report.

Do not leave TTL-compatible CMOS inputs floating at any time during operation. Unused inputs must be terminated at  $V_{CC}$  or GND. If a system will not be actively driving an input at all times, a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; however, a 10-k $\Omega$  resistor is recommended and will typically meet all requirements.

#### 8.3.3 Clamp Diode Structure

As Figure 8-1 shows, the outputs to this device have both positive and negative clamping diodes, and the inputs to this device have negative clamping diodes only.

#### **CAUTION**

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



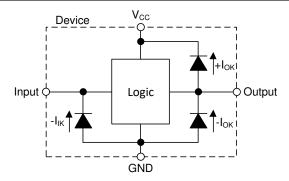


Figure 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

#### **8.4 Device Functional Modes**

Table 8-1. Function Table (Each Gate)

INP	OUTPUT	
Α	В	Y
Н	Н	L
L	Х	Н
Х	L	Н



## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### 9.1 Application Information

In this application, two 2-input NAND gates are used to create an active-low SR latch as shown in Figure 9-1. The two additional gates can be used for a second SR latch, or the inputs can be grounded and both channels left unused.

The AHCT00 is used to drive the tamper indicator LED and provide one bit of data to the system controller. When the tamper switch outputs LOW, the output Q becomes HIGH. This output remains HIGH until the system controller addresses the event and sends a LOW signal to the  $\overline{\mathbb{R}}$  input which returns the Q output back to LOW.

The inputs of this active-low SR latch can often be driven by open-drain outputs which can produce slow input transition rates when they transition from LOW to Hi-Z. This makes the AHCT00 ideal for the application because it has Schmitt-trigger inputs that do not have input transition rate requirements.

#### 9.2 Typical Application

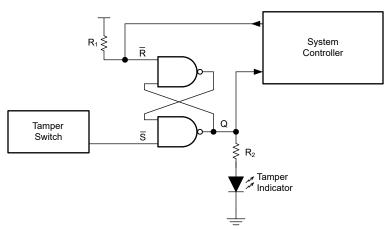


Figure 9-1. Typical Application Block Diagram

#### 9.2.1 Design Requirements

#### 9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the AHCT00 plus the maximum static supply current,  $I_{CC}$ , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through  $V_{CC}$  listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the AHCT00 plus the maximum supply current, I<sub>CC</sub>, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.



The AHCT00 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The AHCT00 can drive a load with total resistance described by  $R_L \ge V_O / I_O$ , with the output voltage and current defined in the *Electrical Characteristics* table with  $V_{OH}$  and  $V_{OL}$ . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the  $V_{CC}$  pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

#### **CAUTION**

The maximum junction temperature,  $T_{J(max)}$  listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

#### 9.2.1.2 Input Considerations

Input signals must cross  $V_{IL(max)}$  to be considered a logic LOW, and  $V_{IH(min)}$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either  $V_{CC}$  or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the AHCT00 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10-k $\Omega$  resistor value is often used due to these factors.

The AHCT00 has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

#### 9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V<sub>CC</sub> or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

#### 9.2.2 Detailed Design Procedure

 Add a decoupling capacitor from V<sub>CC</sub> to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V<sub>CC</sub> and GND pins. An example layout is shown in the *Layout* section.

- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; it will, however, ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the AHCT00 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than  $(V_{CC} / I_{O(max)}) \Omega$ . This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in M $\Omega$ ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

#### 9.2.3 Application Curves

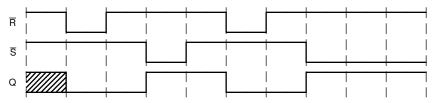


Figure 9-2. Application Timing Diagram

#### 9.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in *Layout Example*.

#### 9.4 Layout

#### 9.4.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V<sub>CC</sub>, whichever makes more sense for the logic function or is more convenient.

#### 9.4.2 Layout Example

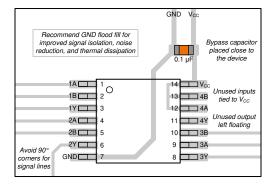


Figure 9-3. Example Layout for the AHCT00



## 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

#### **10.1 Documentation Support**

#### 10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, CMOS Power Consumption and Cpd Calculation application note
- Texas Instruments, Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices application note

## 10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 10.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 10.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 10.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

#### 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com

22-Jan-2025

## **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9682301Q2A	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9682301Q2A SNJ54AHCT 00FK	Samples
5962-9682301QCA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9682301QC A SNJ54AHCT00J	Samples
5962-9682301QDA	ACTIVE	CFP	W	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9682301QD A SNJ54AHCT00W	Samples
SN74AHCT00BQAR	ACTIVE	WQFN	BQA	14	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT00	Samples
SN74AHCT00D	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-40 to 85	AHCT00	
SN74AHCT00DBR	ACTIVE	SSOP	DB	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HB00	Samples
SN74AHCT00DGVR	ACTIVE	TVSOP	DGV	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HB00	Samples
SN74AHCT00DR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT00	Samples
SN74AHCT00DRE4	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT00	Samples
SN74AHCT00N	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74AHCT00N	Samples
SN74AHCT00NE4	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74AHCT00N	Samples
SN74AHCT00NSR	ACTIVE	SOP	NS	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT00	Samples
SN74AHCT00PW	OBSOLETE	TSSOP	PW	14		TBD	Call TI	Call TI	-40 to 85	HB00	
SN74AHCT00PWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	HB00	Samples
SN74AHCT00RGYR	ACTIVE	VQFN	RGY	14	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	HB00	Samples
SNJ54AHCT00FK	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9682301Q2A SNJ54AHCT 00FK	Samples

## PACKAGE OPTION ADDENDUM

www.ti.com 22-Jan-2025

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SNJ54AHCT00J	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9682301QC A SNJ54AHCT00J	Samples
SNJ54AHCT00W	ACTIVE	CFP	W	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9682301QD A SNJ54AHCT00W	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

## **PACKAGE OPTION ADDENDUM**

www.ti.com 22-Jan-2025

#### OTHER QUALIFIED VERSIONS OF SN54AHCT00, SN74AHCT00:

● Catalog : SN74AHCT00

● Enhanced Product : SN74AHCT00-EP, SN74AHCT00-EP

• Military : SN54AHCT00

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

• Military - QML certified for Military and Defense Applications



www.ti.com 7-Dec-2024

#### TAPE AND REEL INFORMATION



# TAPE DIMENSIONS KO P1 BO W Cavity A0

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHCT00BQAR	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74AHCT00DBR	SSOP	DB	14	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74AHCT00DGVR	TVSOP	DGV	14	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74AHCT00DR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74AHCT00NSR	SOP	NS	14	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
SN74AHCT00PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT00PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT00RGYR	VQFN	RGY	14	3000	330.0	12.4	3.75	3.75	1.15	8.0	12.0	Q1



www.ti.com 7-Dec-2024



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHCT00BQAR	WQFN	BQA	14	3000	210.0	185.0	35.0
SN74AHCT00DBR	SSOP	DB	14	2000	356.0	356.0	35.0
SN74AHCT00DGVR	TVSOP	DGV	14	2000	356.0	356.0	35.0
SN74AHCT00DR	SOIC	D	14	2500	356.0	356.0	35.0
SN74AHCT00NSR	SOP	NS	14	2000	356.0	356.0	35.0
SN74AHCT00PWR	TSSOP	PW	14	2000	356.0	356.0	35.0
SN74AHCT00PWR	TSSOP	PW	14	2000	353.0	353.0	32.0
SN74AHCT00RGYR	VQFN	RGY	14	3000	356.0	356.0	35.0





www.ti.com 7-Dec-2024

#### **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
5962-9682301Q2A	FK	LCCC	20	55	506.98	12.06	2030	NA
5962-9682301QDA	W	CFP	14	25	506.98	26.16	6220	NA
SN74AHCT00N	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT00N	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT00NE4	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT00NE4	N	PDIP	14	25	506	13.97	11230	4.32
SNJ54AHCT00FK	FK	LCCC	20	55	506.98	12.06	2030	NA
SNJ54AHCT00W	W	CFP	14	25	506.98	26.16	6220	NA

3.5 x 3.5, 0.5 mm pitch

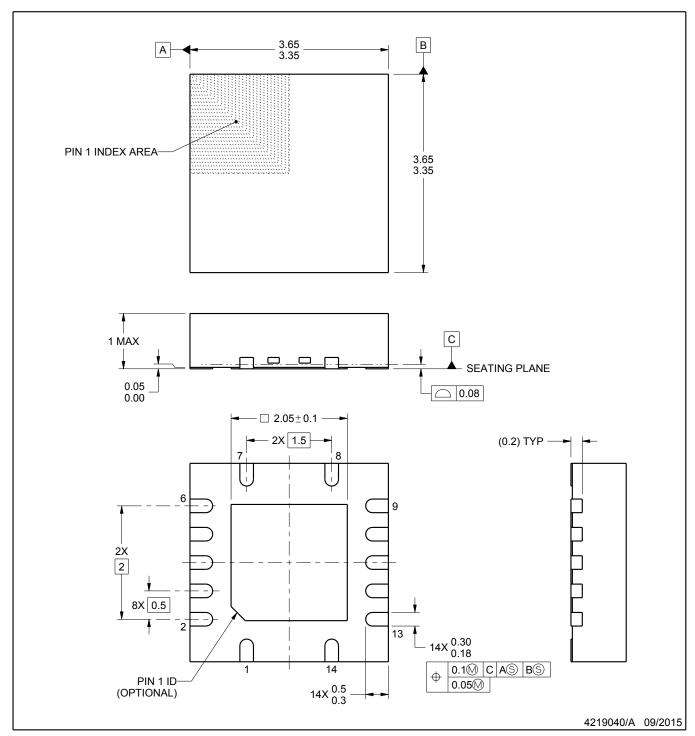
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PLASTIC QUAD FLATPACK - NO LEAD



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
   The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE INTEGRATED CIRCUIT



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



INSTRUMENTS www.ti.com

PLASTIC QUAD FLAT PACK-NO LEAD



- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

## **MECHANICAL DATA**

## NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

#### PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



8.89 x 8.89, 1.27 mm pitch

LEADLESS CERAMIC CHIP CARRIER

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
   Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
   Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



## N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# W (R-GDFP-F14)

## CERAMIC DUAL FLATPACK



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL STD 1835 GDFP1-F14







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



#### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025. Texas Instruments Incorporated